Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/892,312	LEE, SIEW FEI
Examiner	Art Unit

Kevin M. Nguyen

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	SEAR	CHED	
Class	Subclass	Date	Examiner
345	156	11/7/2005	KMN
200	5A, 5R	11/7/2005	KMN
200	11R, 314	11/7/2005	KMN
200	336	11/7/2005	KMN
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INT	ERFERENC	CE SEARCH	ED
Class	Subclass	Date	Examiner
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(INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
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